

Search Notes

Application/Control No.

09/623,373

Examiner

Hien Tran

Applicant(s)/Patent under
Reexamination

HEED, BJORN

Art Unit

1764

SEARCHED

Class	Subclass	Date	Examiner
422	173,175, 177,172	2/23/2004	HT
431	5,7,170	2/23/2004	HT
432	180,181	2/23/2004	HT
122	4D	2/23/2004	HT
updated	search	10/6/2004	HT
updated	search	6/10/2005	HT
updated	search	2/28/2006	HT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Image class/subclass search / inventor's name search / text search	2/23/2004	HT